



# STW11NK100Z

N-channel 1000V - 1.1Ω - 8.3A - TO-247  
Zener - Protected SuperMESH™ PowerMOSFET

## General features

Type	V <sub>DSS</sub> (@T <sub>Jmax</sub> )	R <sub>DS(on)</sub>	I <sub>D</sub>	P <sub>w</sub>
STW11NK100Z	1000 V	< 1.38 Ω	8.3 A	230W

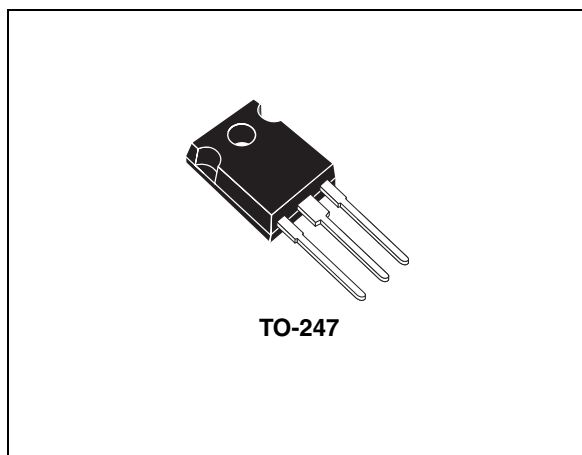
- Extremely high dv/dt capability
- 100% avalanche tested
- Gate charge minimized
- Very low intrinsic capacitances
- Very good manufacturing repeatability

## Description

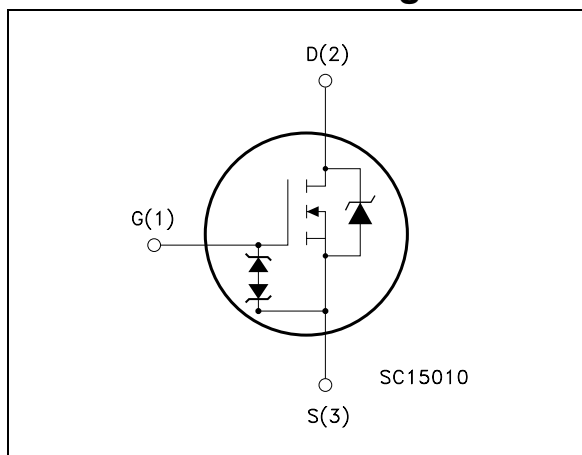
The SuperMESH™ series is obtained through an extreme optimization of ST's well established strip-based PowerMESH™ layout. In addition to pushing on-resistance significantly down, special care is taken to ensure a very good dv/dt capability for the most demanding applications. Such series complements ST full range of high voltage MOSFETs including revolutionary MDmesh™ products.

## Applications

- Switching application



## Internal schematic diagram



## Order codes

Part number	Marking	Package	Packaging
STW11NK100Z	W11NK100Z	TO-247	Tube

## Contents

<b>1</b>	<b>Electrical ratings</b> .....	<b>3</b>
<b>2</b>	<b>Electrical characteristics</b> .....	<b>5</b>
	2.1 Electrical characteristics (curves) .....	7
<b>3</b>	<b>Test circuit Package mechanical data</b> .....	<b>10</b>
<b>4</b>	<b>Package mechanical data</b> .....	<b>11</b>
<b>5</b>	<b>Revision history</b> .....	<b>13</b>

# 1 Electrical ratings

**Table 1. Absolute maximum ratings**

Symbol	Parameter	Value	Unit
$V_{DS}$	Drain-source voltage ( $V_{GS} = 0$ )	1000	V
$V_{DGR}$	Drain-gate voltage ( $R_{GS} = 20K\Omega$ )	1000	V
$V_{GS}$	Gate-source voltage	$\pm 30$	V
$I_D$	Drain current (continuous) at $T_C = 25^\circ C$	8.3	A
$I_D$	Drain current (continuous) at $T_C = 100^\circ C$	5.2	A
$I_{DM}^{(1)}$	Drain current (pulsed)	33.2	A
$P_{TOT}$	Total dissipation at $T_C = 25^\circ C$	230	W
	Derating Factor	1.85	W/ $^\circ C$
$V_{ESD (G-S)}$	Gate source ESD(HBM-C=100pF, R=1,5K $\Omega$ )	6000	V
$dv/dt^{(2)}$	Peak diode recovery voltage slope	4.5	V/ns
$T_J$ $T_{stg}$	Operating junction temperature Storage temperature	-55 to 150	$^\circ C$

1. Pulse width limited by safe operating area

2.  $I_{SD} \leq 8.3$  A,  $di/dt \leq 200$  A/ $\mu s$ ,  $V_{DD} \leq V_{(BR)DSS}$ ,  $T_j \leq T_{JMAX}$

**Table 2. Thermal data**

Symbol	Parameter	Value	Unit
$R_{thj-case}$	Thermal resistance junction-case Max	0.54	$^\circ C/W$
$R_{thj-a}$	Thermal resistance junction-ambient Max	50	$^\circ C/W$
$T_l$	Maximum lead temperature for soldering purpose	300	$^\circ C$

**Table 3. Avalanche characteristics**

Symbol	Parameter	Value	Unit
$I_{AR}$	Avalanche current, repetitive or not-repetitive (pulse width limited by $T_j$ Max)	8.3	A
$E_{AS}$	Single pulse avalanche energy (starting $T_j = 25^\circ C$ , $I_d = I_{AR}$ , $V_{dd} = 50V$ )	550	mJ

**Table 4. Gate-source zener diode**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$BV_{GSO}$	Gate-source breakdown voltage	$I_{gs}=\pm 1\text{mA}$ (Open Drain)	30		0	V

### Protection features of gate-to-source zener diodes

The built-in back-to-back Zener diodes have specifically been designed to enhance not only the device's ESD capability, but also to make them safely absorb possible voltage transients that may occasionally be applied from gate to source. In this respect the Zener voltage is appropriate to achieve an efficient and cost-effective intervention to protect the device's integrity. These integrated Zener diodes thus avoid the usage of external components.

## 2 Electrical characteristics

( $T_{CASE}=25^{\circ}C$  unless otherwise specified)

**Table 5. On/off states**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$I_D = 1mA, V_{GS} = 0$	1000			V
$I_{DSS}$	Zero gate voltage drain current ( $V_{GS} = 0$ )	$V_{DS} = \text{Max rating},$ $V_{DS} = \text{Max rating},$ $T_c = 125^{\circ}C$			1 50	$\mu A$ $\mu A$
$I_{GSS}$	Gate body leakage current ( $V_{GS} = 0$ )	$V_{GS} = \pm 20V$			$\pm 10$	$\mu A$
$V_{GS(th)}$	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 100\mu A$	3	3.75	4.5	V
$R_{DS(on)}$	Static drain-source on resistance	$V_{GS} = 10V, I_D = 4.15 A$		1.1	1.38	$\Omega$

**Table 6. Dynamic**

Symbol	Parameter	Test conditions	Min.	Typ.	Max.	Unit
$g_{fs}^{(1)}$	Forward transconductance	$V_{DS} = 15V, I_D = 4.15A$		9		S
$C_{iss}$	Input capacitance	$V_{DS} = 25V, f = 1 \text{ MHz}, V_{GS} = 0$		3500		pF
$C_{oss}$	Output capacitance			270		pF
$C_{rss}$	Reverse transfer capacitance			60		pF
$C_{osseq}^{(2)}$	Equivalent output capacitance	$V_{GS} = 0, V_{DS} = 0V \text{ to } 500V$		170		pF
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 800V, I_D = 8A,$ $R_G = 4.7\Omega, V_{GS} = 10V$ (see <a href="#">Figure 16</a> )		27		ns
$t_r$	Rise time			18		ns
$t_{d(off)}$	Off-voltage rise time			98		ns
$t_f$	Fall time			55		ns
$Q_g$	Total gate charge	$V_{DD} = 800V, I_D = 8A$ $V_{GS} = 10V$		113	162	nC
$Q_{gs}$	Gate-source charge			18		nC
$Q_{gd}$	Gate-drain charge			60		nC

1. Pulsed: pulse duration=300 $\mu s$ , duty cycle 1.5%

2.  $C_{oss \text{ eq}}$  is defined as a constant equivalent capacitance giving the same charging time as  $C_{oss}$  when  $V_{DS}$  increases from 0 to 80%  $V_{DSS}$

**Table 7. Source drain diode**

Symbol	Parameter	Test conditions	Min	Typ.	Max	Unit
$I_{SD}$	Source-drain current				8.3	A
$I_{SDM}^{(1)}$	Source-drain current (pulsed)				33.2	A
$V_{SD}^{(2)}$	Forward on voltage	$I_{SD}=8.3A, V_{GS}=0$			1.6	V
$t_{rr}$	Reverse recovery time	$I_{SD}=8.3,$ $di/dt = 100A/\mu s,$ $V_{DD}=80V, T_j=25^\circ C$ (see <a href="#">Figure 18</a> )		560		ns
$Q_{rr}$	Reverse recovery charge			4.48		$\mu C$
$I_{RRM}$	Reverse recovery current			16		A
$t_{rr}$	Reverse recovery time	$I_{SD}=8A,$ $di/dt = 100A/\mu s,$ $V_{DD}=80V, T_j=150^\circ C$ (see <a href="#">Figure 18</a> )		620		ns
$Q_{rr}$	Reverse recovery charge			4.57		$\mu C$
$I_{RRM}$	Reverse recovery current			16		A

1. Pulse width limited by safe operating area
2. Pulsed: pulse duration=300 $\mu s$ , duty cycle 1.5%

## 2.1 Electrical characteristics (curves)

Figure 1. Safe operating area

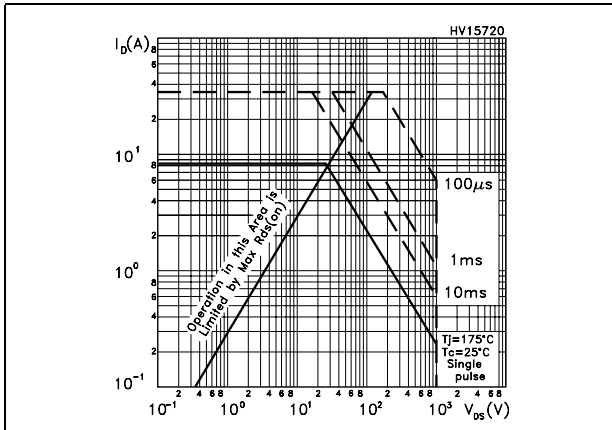


Figure 2. Thermal impedance

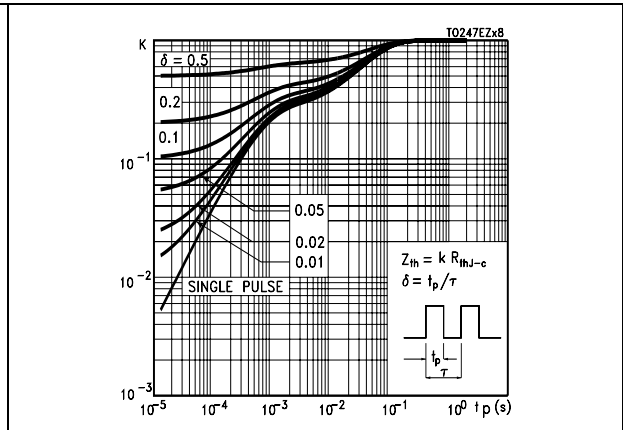


Figure 3. Output characteristics

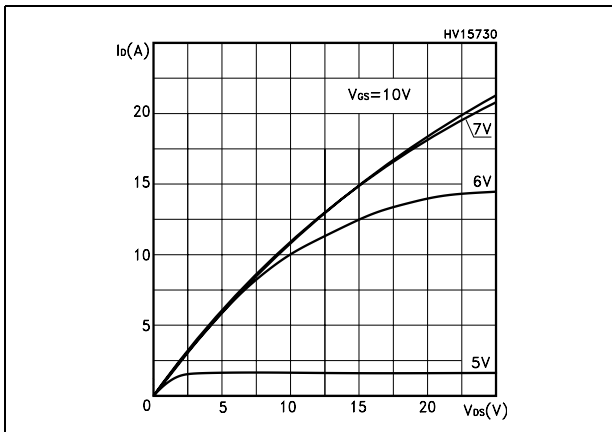


Figure 4. Transfer characteristics

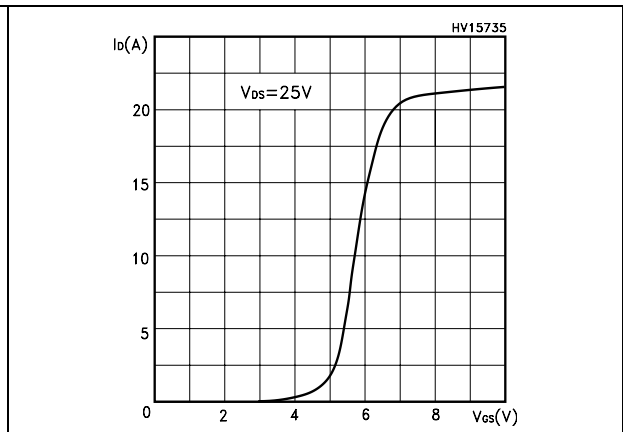


Figure 5. Transconductance

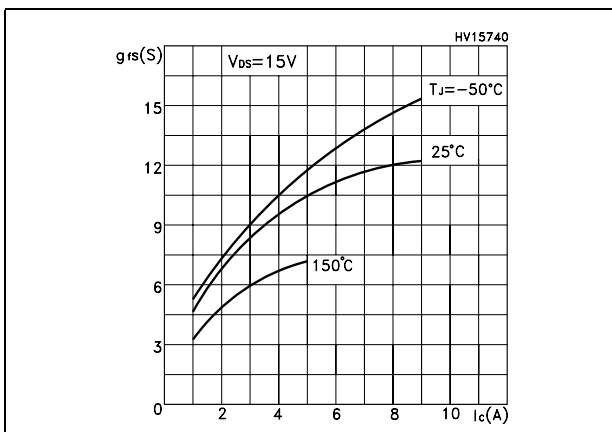


Figure 6. Static drain-source on resistance

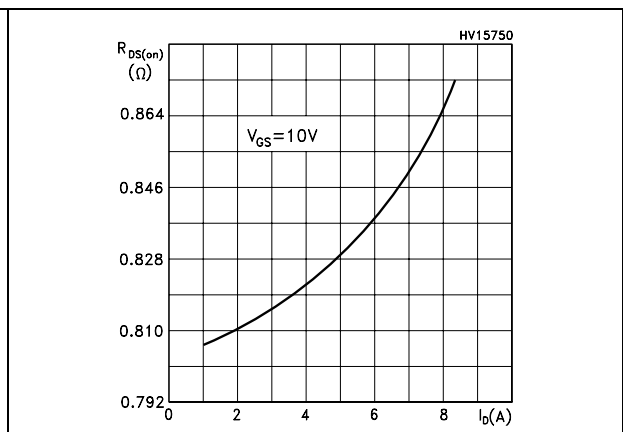


Figure 7. Gate charge vs gate-source voltage Figure 8. Capacitance variations

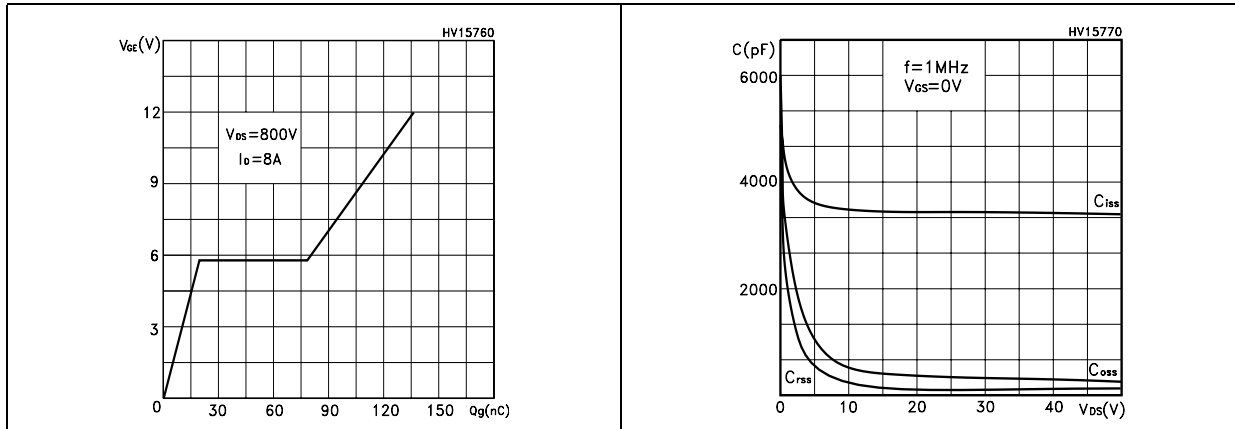


Figure 9. Normalized gate threshold voltage vs temperature Figure 10. Normalized on resistance vs temperature

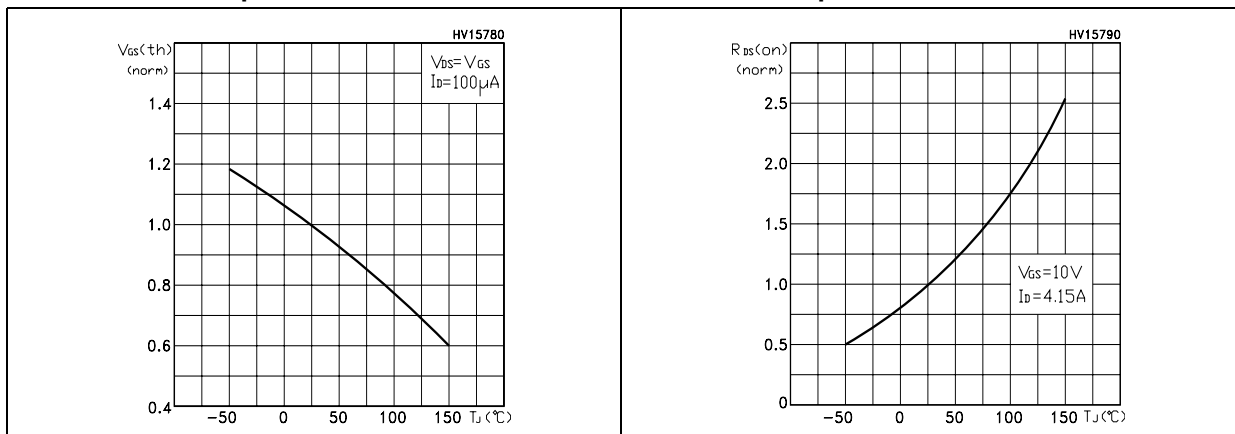


Figure 11. Source-drain diode forward characteristics Figure 12. Normalized  $B_{V_{DSS}}$  vs temperature

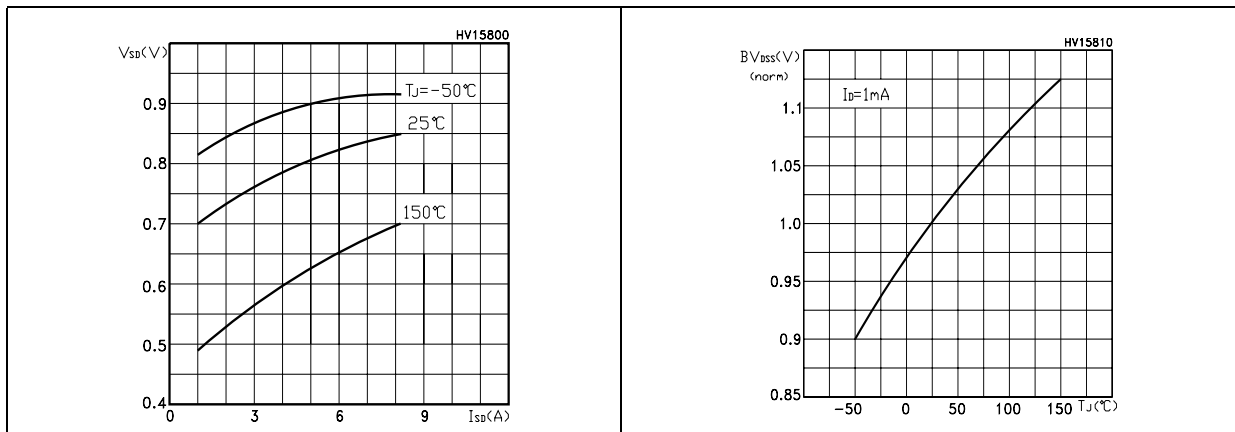
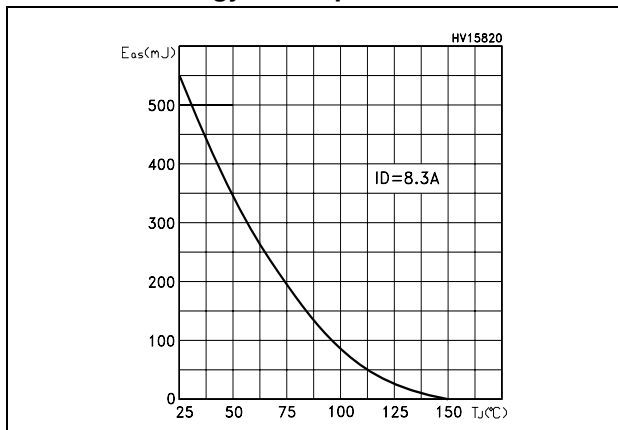




Figure 13. Maximum avalanche energy vs temperature



### 3 Test circuit Package mechanical data

Figure 14. Unclamped Inductive load test circuit

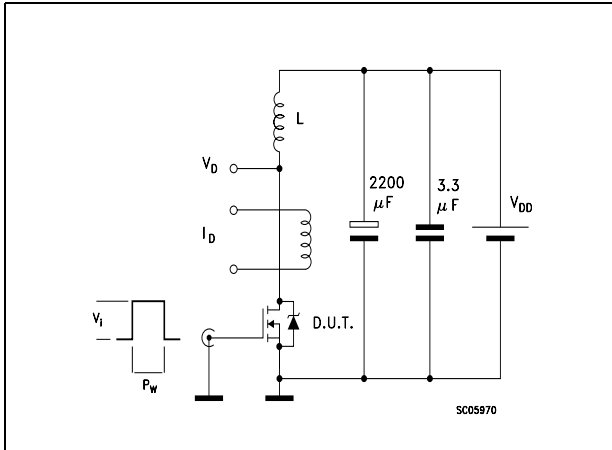


Figure 15. Unclamped Inductive waveform

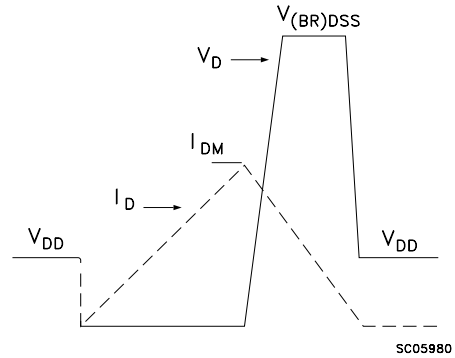


Figure 16. Switching times test circuit for resistive load

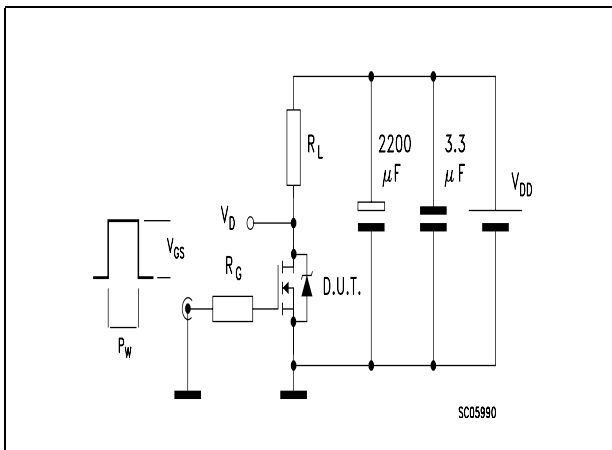


Figure 17. Gate charge test circuit

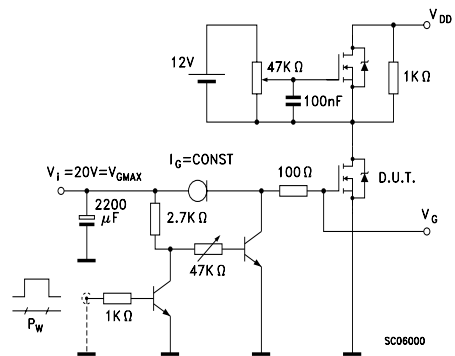
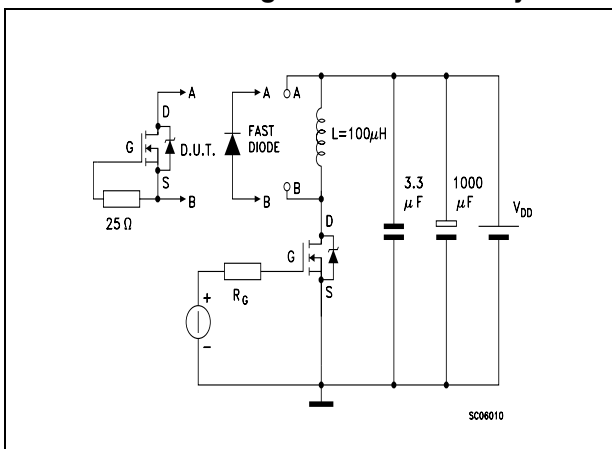


Figure 18. Test circuit for inductive load switching and diode recovery times

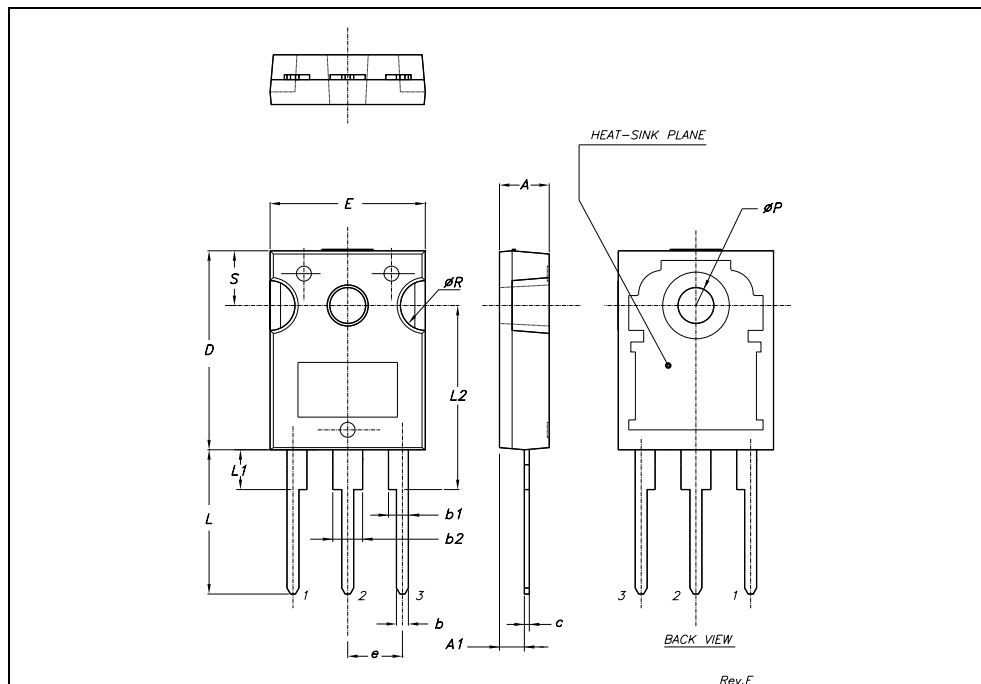


## 4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect . The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at: [www.st.com](http://www.st.com)

**TO-247 MECHANICAL DATA**

DIM.	mm.			inch		
	MIN.	TYP.	MAX.	MIN.	TYP.	MAX.
A	4.85		5.15	0.19		0.20
A1	2.20		2.60	0.086		0.102
b	1.0		1.40	0.039		0.055
b1	2.0		2.40	0.079		0.094
b2	3.0		3.40	0.118		0.134
c	0.40		0.80	0.015		0.03
D	19.85		20.15	0.781		0.793
E	15.45		15.75	0.608		0.620
e		5.45			0.214	
L	14.20		14.80	0.560		0.582
L1	3.70		4.30	0.14		0.17
L2		18.50			0.728	
øP	3.55		3.65	0.140		0.143
øR	4.50		5.50	0.177		0.216
S		5.50			0.216	



## 5 Revision history

**Table 8. Revision history**

<b>Date</b>	<b>Revision</b>	<b>Changes</b>
21-Jun-2004	1	Preliminary version
31-Jul-2006	2	New template, no content change.

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